

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10612456	CHEN, YEN-FU
<b>Examiner</b>	<b>Art Unit</b>	
SIMON KE	2174	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
715	779,789,764-768,717,700,709,711,712	1/24/11	PK

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East Text Search (USPub, USPat, Derwent, EPO, JPO); NPL Search	1/24/11	PK

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	East Text Search (USPub, USPat, Derwent, EPO, JPO)	1/24/11	PK